

ABSTRACT

A probe includes a tip portion, an arm portion, a support portion, and a guide portion. The tip portion includes a contact portion that comes into contact with an object to be inspected. The arm portion has a cantilever structure including a connecting arm that links a free end and a fixed end, and the free end is connected to the tip portion. The support portion is connected to the fixed end. The guide portion is connected to an installation area of the arm portion oriented in a tip direction where the object to be inspected is located as viewed from the contact portion, and protrudes in the tip direction from the installation area.

FIG. 1